vapour deposition of tungsten oxide

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1. Introduction

Tungsten oxides have been studied extensively because of their possible applications in electrochromic devices [1] and gas sensors [2]. Thin films of tungsten oxide have been prepared for these applications by various physical and chemical methods of film deposition, often leading to different properties [1]. In particular, tungsten oxide thin films have been prepared by a range of chemical vapour deposition (CVD) techniques. CVD is an important method of preparation of thin films as it has advantages such as conformal coverage, high purity of films, low temperature processing and economy of large scale coatings. $WO₃$ films have been grown by low-pressure CVD using tungsten hexacarbonyl $(W(CO)_{6})$ as precursor [3] which is highly toxic and also using tungsten alkoxides as precursor [4]. Other precursors such as tungsten oxychloride (WOCl₄) [5] and tungsten hexafluoride (WF₆) [6] have also been used for CVD of tungsten oxide. However, these precursors have problems such as high reactivity, corrosivity and difficulty in handling.

In 1996, the use of volatile tungsten(VI) oxo alkoxide- β diketonate complexes of the type [WO(OR)3L] (R = isopropyl (*ⁱ* Pr),

ABSTRACT

A new series of tungsten complexes, tungsten(VI) oxo-alkoxide-β-ketoesterate comple thesized and characterized by infrared and NMR spectroscopy. Thermogravimetric carried out on the complexes as a function of temperature, and isothermally as a function the thermal analysis data, these complexes are evaluated for their suitability as precu ical vapour deposition of tungsten oxide thin films. The vapour pressure of these prec using the Langmuir equation.

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tert-butyl (^tBu); L = acetyl acetonate (acac), hexat tonate (hfac)) as precursors for the metal organ of tungsten oxide was reported $[7]$. However, the of these compounds was not reported therein, n erature. Thermal analysis of precursors is very in application to CVD. Furthermore, the use of fluor for CVD has many disadvantages, due to the high rosivity of the fluorine. It is thus desirable to develop halogenprecursors for CVD, and to examine their volatility analysis.

Here we report the synthesis, characterizat analysis of a related series of compounds, alkoxide β -ketoesterate complexes of the type | R = isopropyl, *tert*-butyl; L = methyl acetoacetate (toacetate (etob). Thermal analysis as a funct temperature allow us to suggest the suitability of for MOCVD applications. Further, from the diff gravimetry data, the vapour pressure of the pre calculated with the Langmuir equation, using a procedure [8].

2. Experimental

The four complexes prepared and studied are I, [WO(O*ⁱ* Pr)3acac] II, [WO(O*^t* Bu)3meob] III and [WO(O*^t*

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was carried out on a Bruker AMX 400 400 MHz spectrometer. C6D6 was used as solvent and TMS was used as reference. Mass spectra of the compounds were recorded on a Micromass ESI-TOF mass spectrometer

Thermogravimetric/differential thermal analysis was carried out on the compounds, both as a function of temperature, and isothermally as a function of time at different temperatures, to examine their suitability as precursors for chemical vapour deposition. The thermal analysis was carried out on a TA Instruments [SD](#page-3-0)T Q600 simultaneous DSC/TGA analyzer. All the TG experiments were carried out in flowing dry nitrogen, with a heating rate of 10° C/min. Abo[ut 15](#page-3-0) mg of the compound was used for the analysis, with alumina as the reference material. Isothermal experiments were carried out by ramping the temperature at 10° C/min to the isothermal temperat[ure,](#page-3-0) [th](#page-3-0)en allowing the system to stay at that temperature for 15 min.

The Langmuir equation [8] was used to calculate the vapour pressure of the precursors.

$$
P = \left[\left(\frac{dm}{dt} \right) \sqrt{\frac{T}{M}} \right] \left[\frac{\sqrt{2\pi R}}{\alpha_1} \right]
$$
 (1)

where *P* is the vapour pressure at temperature *T*, d*m*/d*t* is the rate of weight loss per unit surface area during the TG experiment, *M* is the molecular mass of the material, *R* is the gas constant, and

Fig. 1. TGA plot for the complexes I [WO(O^tBu)₃acac], II [WO(O^tPr)₃acac], III [WO(O*^t* Bu)3meob] and IV [WO(O*^t* Bu)3etob].

calculated as a function of temperature for the complexes III and IV.

3. Results and discussion

The molecular structure of the complexes is

The various complexes I-IV were character spectroscopy. The IR spectra of the complexes s corresponding to the expected IR bands for th bands for $C=O$ and $C=C$ of the ketoesterate lig 1568 and 1531 cm^{-1} respectively. The band for are seen at 1280 and 2940 cm⁻¹ respectively. The bonds are observed around 450 and 670 cm⁻¹, mation of the complex.

The NMR spectra of the compounds I reported earlier [7]. In this work, the $1H$ and 14 tra of the complexes III and IV were recor solvent. The NMR data are consistent with lier for I and II [7]. The NMR data indicates t complexes to be of the type presented above observed at δ = 31.3 ppm in the ¹³C spectrum CH of the meob ligand indicate the structu above. This is further supported by the pres peak at δ = 5.0 ppm in the ¹H NMR spectrum. in the $1H$ and $13C$ NMR spectra can be ass structure.

The mass spectra of the compounds show a ments. Thus, the formation of these compound NMR and mass spectroscopy. Mass spectrosco molecular ion peak, as the complex fragments electron beam, but the fragments observed co the structure.

The weight loss of the complexes was sti of temperature. The graph showing the therm plexes I–IV is given in Fig. 1. It is observed that β -diketonate complexes, the volatility is high e temperatures. However, the volatility of the $\mathfrak f$ plexes is even higher, with weight loss of the occurring in the temperature range $50-150$ °C

Fig. 2. DTG plots for the complexes I, II, III, and IV.

Fig. 4. Plot of $\ln P$ vs. $1/T$ for the complexes III

Fig. 3. (a) Isothermal TGA plots for the complex III [WO(O^tBu)₃ meob]. The rate of mass loss is 0.1247 ± 0.0004 mg/min at 50° C and 0.2612 ± 0.0005 mg/min at 65 °C. (b) Isothermal TGA plots for the complex IV [WO(O^tBu)₃etob]. The rate of mass loss is 0.0770 ± 0.0003 mg/min at $50 °C$, 0.1640 ± 0.0004 at $65 °C$ and 0.3768 ± 0.0006 mg/min at 80 °C.

that, as the size of the ligand L increases, the complex increases. This is to be expected becau ligand, lower is the intermolecular interaction b molecules, and hence higher the volatility. This is mograms of Fig. 1. The very high, single-step w complexes III and IV indicates that they sublime posing.

The differential thermogravimetric (DTG) da Fig. 2. In case of the DTG of I and II, we see mul cating that many processes are involved in the and that the complex is probably decomposing as the complexes III and IV, however, the DTG curve cally, and falls sharply to zero. This indicates that t single step process, and that the process is the zer rate of weight loss is independent of the amount orating. This is a property that is highly desirable CVD.

The weight loss of the complexes III and I isothermally at different temperatures, as a fund results are shown in Fig. 3a and b. In both cases, linear with time. This is a very desirable property chemical vapour deposition. The rates of weight l along with Fig. 3a and b respectively.

The vapour pressure data for complexes III and IV and I in Fig. 4, as a plot of $\ln P$ vs. $1/T$. The plots are straight slope of which yields the enthalpy of sublimation. the enthalpies of sublimation of III and IV were 46.3 ± 0.7 and 42.7 ± 0.7 kJ/mol, respectively.

The high volatility at moderate temperatures the linearity of the weight loss with time, indic ketoesterate complexes exhibit the characteristics precursors for the chemical vapour deposition of thin films. The precursors are also found to b periods, more than six months, when stored und conditions. This has been verified by carrying out on stored precursors, and finding that the TGA ant even after six months of storage. The CVD of films using these complexes as precursors is presently The tungsten complexes reported here are relatively less toxic and/or easier to handle than tungsten l tungsten alkoxide complexes that have often beer of tungsten oxide thin films.

4. Conclusion

The results indicate that of the four complexes evaluated, the two new complexes [WO(O^tBu)₃meob] and [WO(O^tBu)₃etob] are promising precursors for the chemical vapour deposition of tungsten oxide thin films.

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